V00145

Die; 2222; 795; S; 1M; S5,S6,S7; 0.13mW; 0.16X0.20

Applications

- Atomic Clock
- Magnetometer

Features:

- Package Description: Bare Die
- Chip Technology: GaAs VCSEL
- Laser Wavelength: 795 nm
- Radiation Profile: Single Mode
- ESD: 250 V acc. to ANSI/ESDA/JEDEC JS-001 (HBM, Class 1A)

Ordering Information

Description	Operating Mode:	Ordering Code
Group 1 - Die; 2222; 795; S; 1M; S5,S6,S7; 0.13mW; 0.16X0.20	T _a = 60±10°C; I _F = 1.4 mA; DC = 100%, 795nm	V00145 Group: 1
Group 2 - Die; 2222; 795; S; 1M; S5,S6,S7; 0.13mW; 0.16X0.20	T _a = 70±10°C; I _F = 1.4 mA; DC = 100%, 795nm	V00145 Group: 2
Group 3 - Die; 2222; 795; S; 1M; S5,S6,S7; 0.13mW; 0.16X0.20	T _a = 80±10°C; I _F = 1.4 mA; DC = 100%, 795nm	V00145 Group: 3
Group 4 - Die; 2222; 795; S; 1M; S5,S6,S7; 0.13mW; 0.16X0.20	T _a = 90±10°C; I _F = 1.4 mA; DC = 100%, 795nm	V00145 Group: 4
Group 5 - Die; 2222; 795; S; 1M; S5,S6,S7; 0.13mW; 0.16X0.20	T _a = 100±10°C; I _F = 1.4 mA; DC = 100%, 795nm	V00145 Group: 5



COMPLIES WITH IEC 60825-1, 3rd EDITION MAY 2014. COMPLIES WITH 21 CFR 1040.10 AND 1040-10.11 EXCEPT FOR DEVIATIONS PURSUANT TO LASER NOTICE NO.50 DATED 27 MAY 2001.



Maximum Ratings

 $T_a = 80^{\circ}C$

Parameter	Symbol		Values
Operation/Solder temperature	Ts	min.	-20°C
DC = 100%		max.	110°C
Storage temperature	Tstg	min.	-40°C
		max.	125°C
Forward current to remain single mode	lf	max.	1.5 mA
Direct current operation; DC = 100%; Ts = 75° C			
Forward Current	lf	max.	3mA
Direct current operation; DC = 100%; Ts = 75° C			
Reverse Voltage	Not design	ed for reverse	operation
ESD withstand voltage	Vesd	max.	250 V
acc. to ANSI/ESDA/JEDEC JS-001 (HBM, Class 1A)			

Note: Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device.



Characteristics

 $T_a = 80^{\circ}C$, $I_F = 1.4 \text{ mA}$; DC = 100% - Group 3

Parameter	Symbol		Values
Forward voltage	Vf	typ.	1.8 V
Output power	Φ	typ.	0.13 mW
Threshold current	lth	typ.	0.75 mA
Slope efficiency	SE	typ.	0.21 W / A
Single-mode Suppression Ratio	SMSR	min.	20 dB
Polarization Extinction Ratio 5)	PER	min.	15 dB
Peak wavelength (vaccum)	λ_{peak-v}	min.	794.5 nm
		typ.	795 nm
		max.	795.5 nm
Spectral linewidth	$\Lambda_{ ext{linewidth}}$	max.	100 MHz
FM Modulation Bandwith	Fm	min.	3.4 GHz
Temperature coefficient of wavelength	TC_{λ}	typ.	0.055 nm / K
Field of view at FWHM (50% of Φ_{max})	\$ x	typ.	12°
	Φ Υ	typ.	12°
Field of view at 1/e ²	\$ x	typ.	20°
	$oldsymbol{\phi}_{ ext{Y}}$	typ.	20°

Note: Wavelength, Output power and Voltage changes based on operating temp.



Relative Spectral Emission ¹⁾



Radiation Characteristics ¹⁾





Forward Voltage ^{1) 2)}



Optical Output Power ^{1) 2)}





Dimension Drawings³⁾



Product Label

VIXAR Vertical Cavity Surface Emitting Laser (VCSEL) Product			
Model: G	Group:		
Manufacturer:	VIXAR INC. 2355 POLARIS AVE N Plymouth, MN 55447, U	. SUITE 100 JSA	
Manufactured:	Bare Die by VIXAR, Fabricated or Packaged Vixar, Inc. 2355 POLARIS AVE N Plymouth, MN 55447, U	d by: . SUITE 100 JSA	
Wafer #: Mft Lot #: Date Code: Quantity:			
Complies with FDA/CDRH 21 CFR 1040.10 and 1040.11 except For deviations pursuant to Laser Notice No. 50, dated June 24, 2007.			
CDRH Accession No.: 1210159-000 Product Code: 95RDW			



Packaging



Note: For sampling quantities please contact sales@vixarinc.com



Notes

Depending on the mode of operation, these devices emit highly concentrated visible and non-visible light which can be hazardous to the human eye. Products which incorporate these devices must follow the safety precautions given in IEC 60825-1.

Subcomponents of this device contain, in addition to other substances, metal filled materials including silver. Metal filled materials can be affected by environments that contain traces of aggressive substances. Therefore, we recommend that customers minimize device exposure to aggressive substances during storage, production, and use. Devices that showed visible discoloration when tested using the described tests above did show no performance deviations within failure limits during the stated test duration. Respective failure limits are described in the IEC60810.

For further application related information please <u>http://vixarinc.com/vcsel-technology/application-notes</u>



Glossary

- ¹⁾ **Typical Values**: Due to the special conditions of the manufacturing processes of semiconductor devices, the typical data or calculated correlations of technical parameters can only reflect statistical figures. These do not necessarily correspond to the actual parameters of each single product, which could differ from the typical data and calculated correlations or the typical characteristic line. If requested, e.g. because of technical improvements, these typ. data will be changed without any further notice.
- ²⁾ **Testing temperature:** $TA = 85^{\circ}C \pm 2^{\circ}C$
- ³⁾ **Tolerance of Measure:** Unless otherwise noted in drawing, tolerances are specified with ±0.1 and dimensions are specified in mm.
- ⁴⁾ **Wavelength:** The wavelength is measured at continuous wave, with resolution of ± 0.1 nm.
- ⁵⁾ **Polarization:** The Polarization Extinction Ratio can be degraded under conditions of die stress induced by mounting or packaging.



Revision History

Version	Date	Change
0.0	September 17 - 2020	Initiation of preliminary datasheet
1.0	October 29 – 2020	Datasheet version 1.0 release
1.1	January 28 – 2021	Dimension Drawings update



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